

杭州云镓半导体科技有限公司
Hangzhou CloudSemi Technology Co., Ltd

GaN Switching Behavior Analysis

GaN Device R&D Team

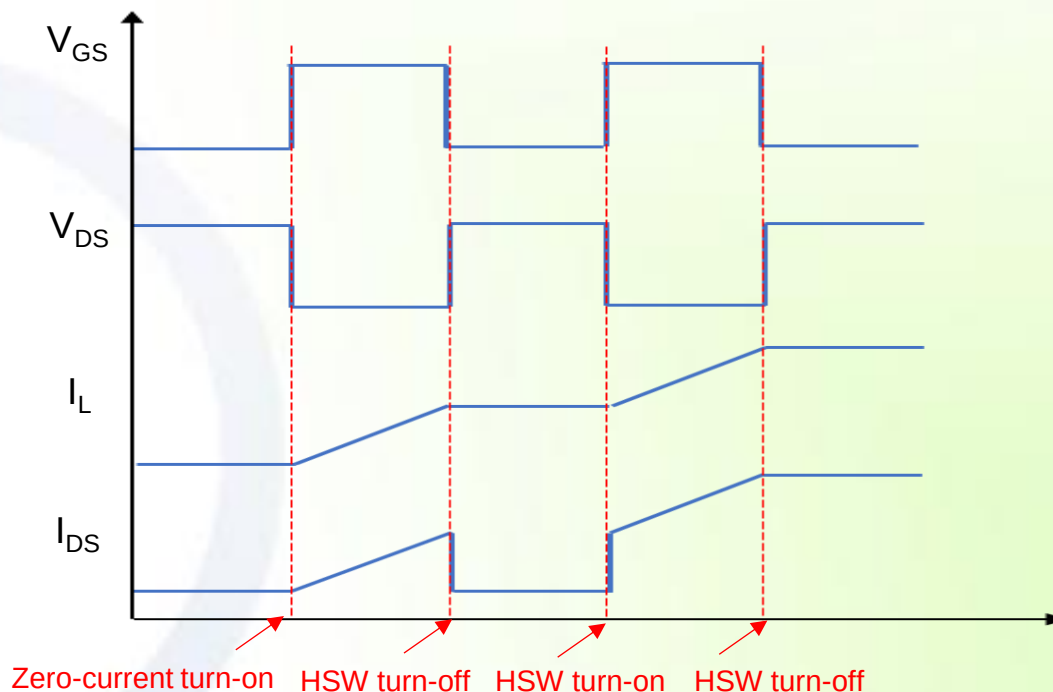
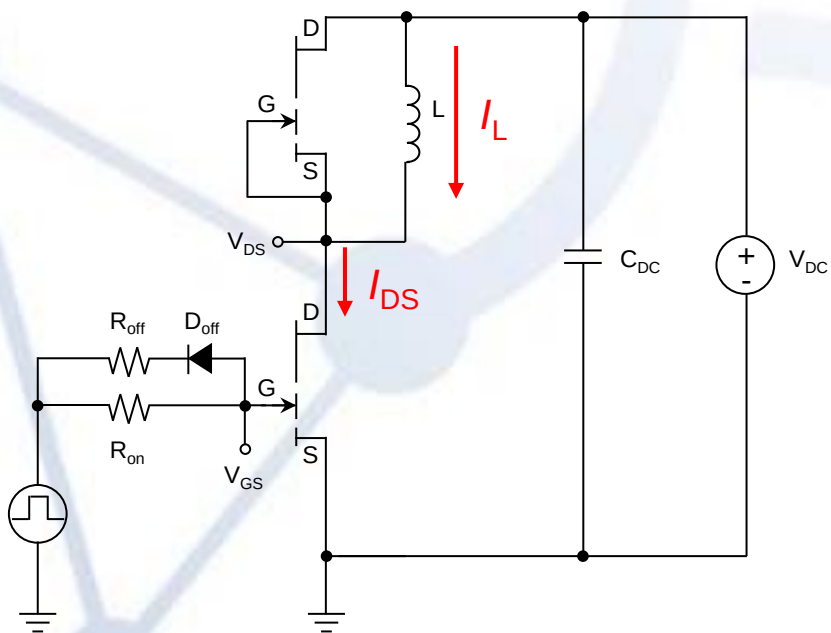
Powering the Dreams!



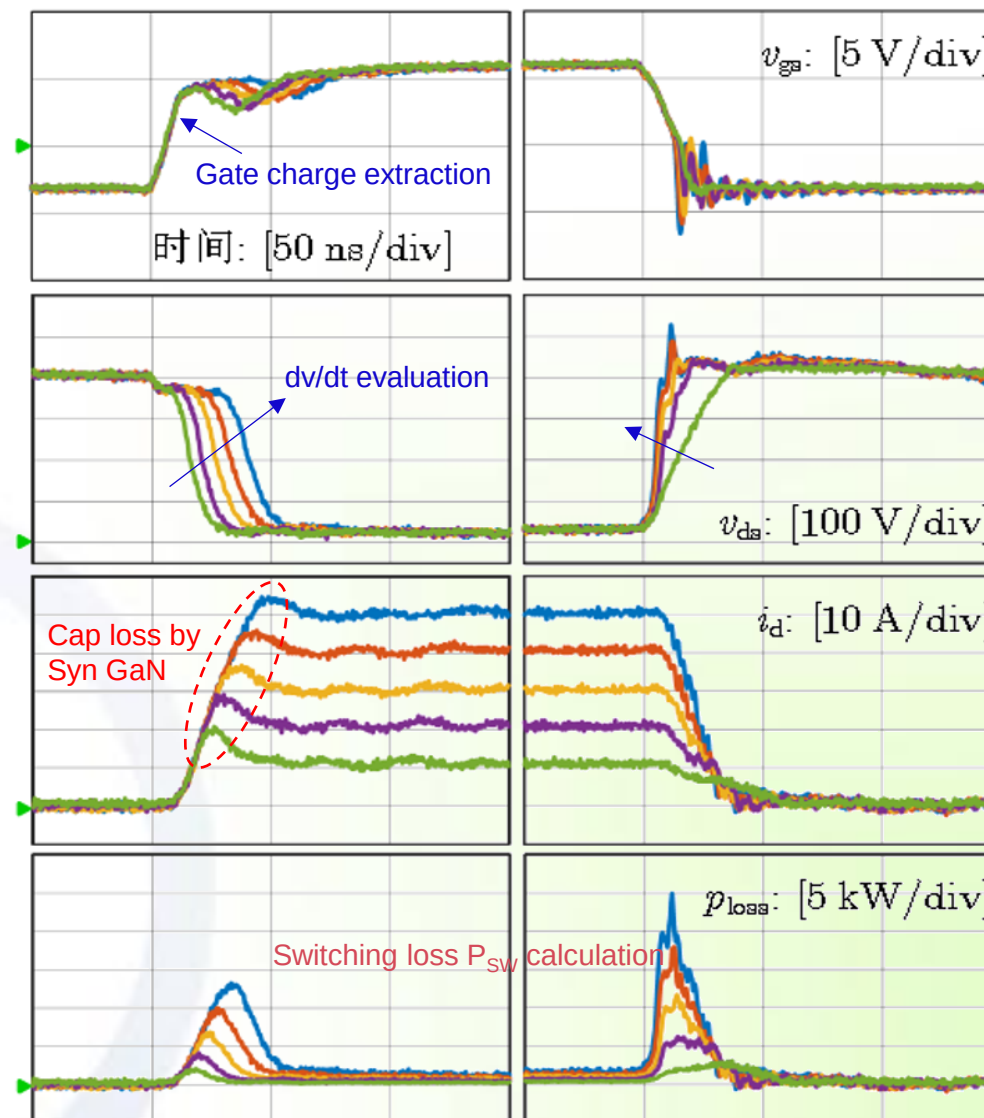
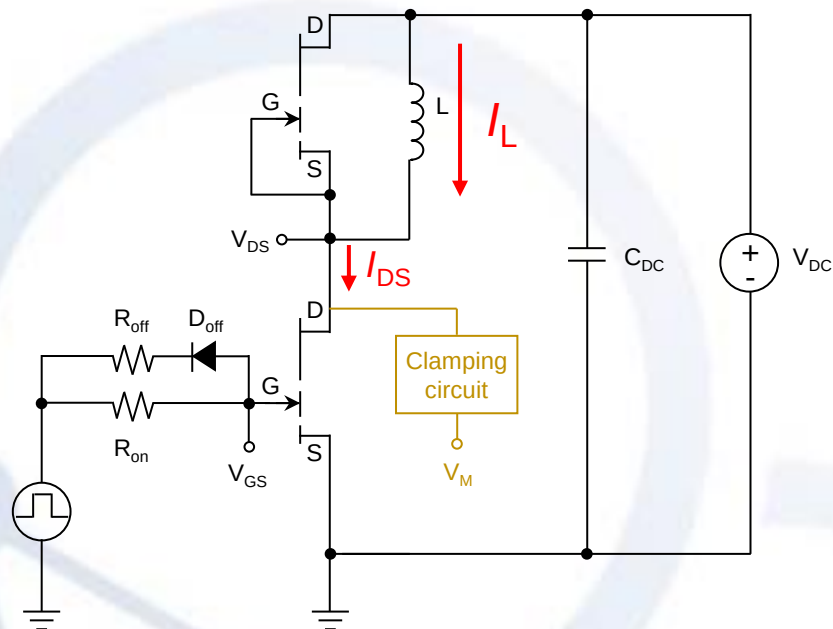
Double pulse tester for GaN FET

Why do we need double pulse tester to measure GaN FETs?

1. Extracting GaN switching parameters (t_{on} , t_{off} , t_r , t_f)
2. Extracting GaN switching loss (E_{on} , E_{off})
3. Emulating the system behavior, e.g. turn-off drain spike, switching time, gate ringing and etc.
4. Evaluating the dynamic performance of GaN, e.g. dynamic R_{dson} , HSW D-HTOL, switching SOA, and etc.
5. No need of high-power equipment, low-cost scheme

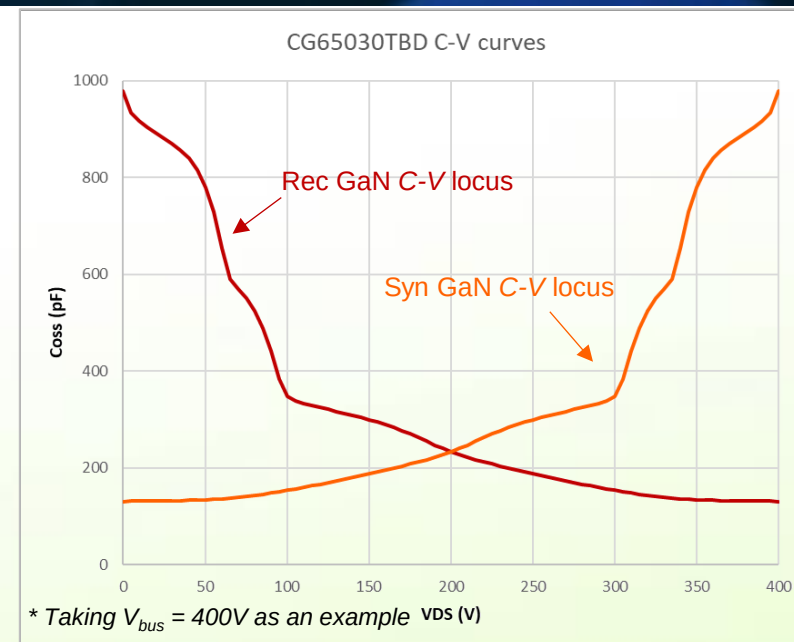
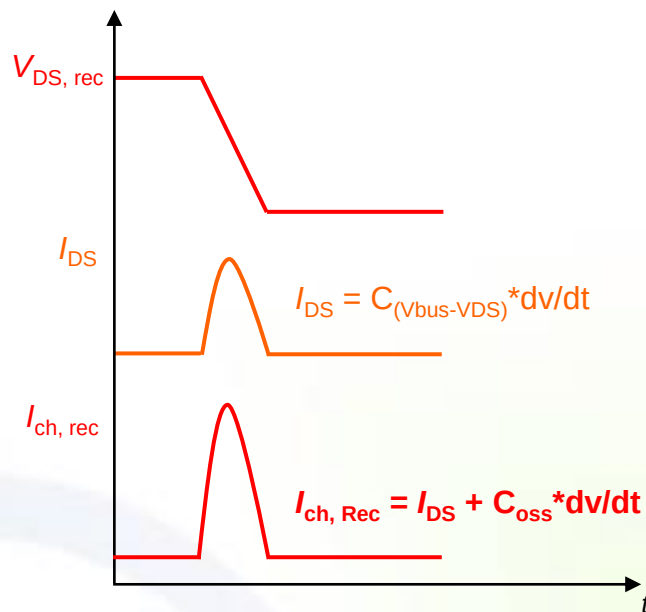
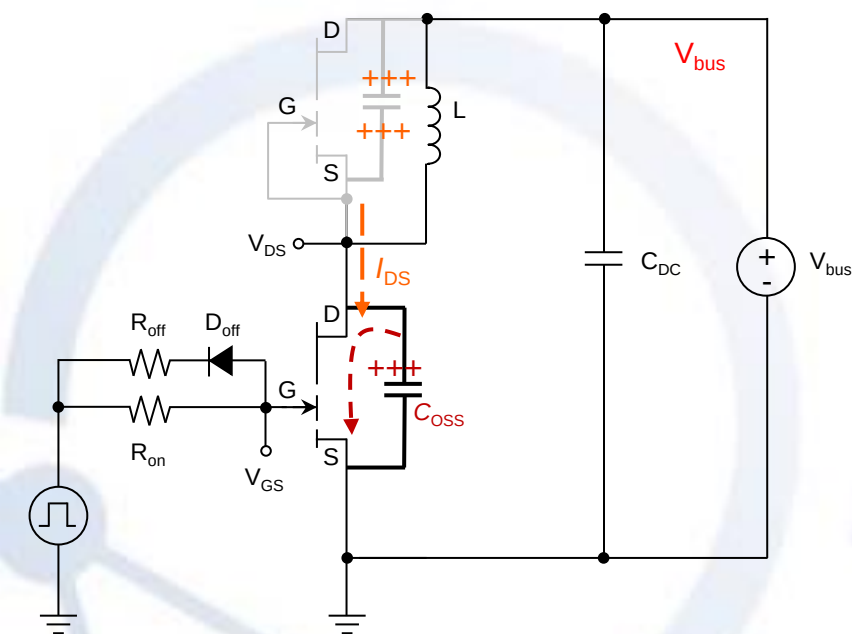


Double pulse tester for GaN FET: example



- 650V/30mΩ CloudSemi E-mode GaN device under test
- Stable switching behavior from HSW DPT test
- Nearly all the dynamic parameters can be extracted from measurement
- Additionally implemented clamping circuit can assist to extract the dynamic R_{dson}

1st pulse turn-on: zero-current capacitive load



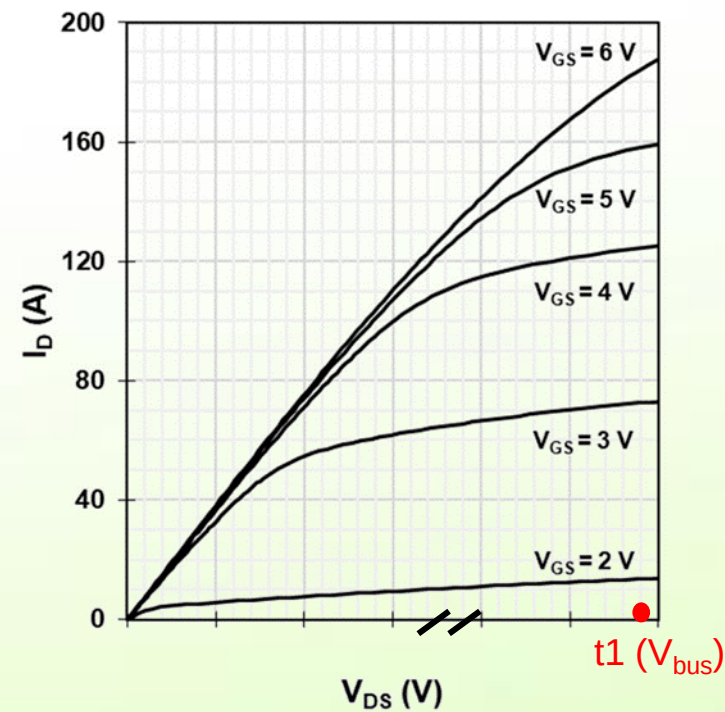
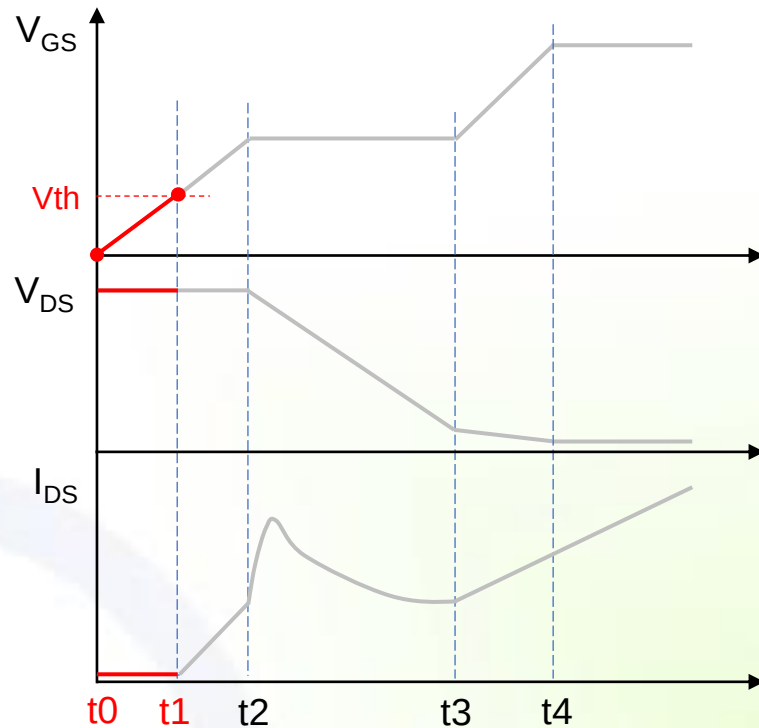
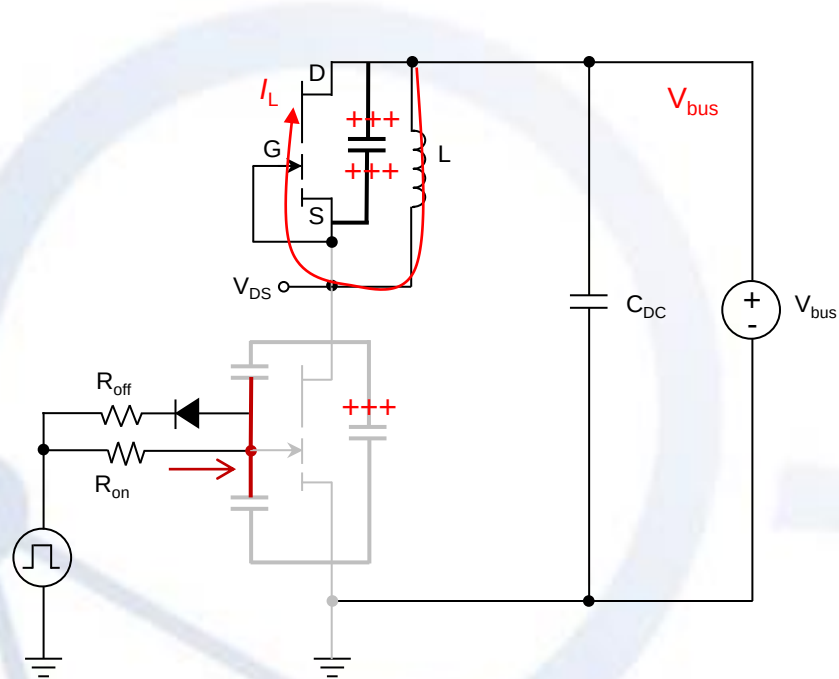
Stage of start-up, zero-current turn-on (capacitive-load switching):

- V_{DS} of rectifier transistor (low-side GaN in this slide): $V_{bus} \rightarrow 0$; V_{DS} of synchronous transistor (high-side GaN in this slide): $0 \rightarrow V_{bus}$
- The setup can be treated as a capacitive-load switching:
 - Oscilloscope-captured I_{DS} comes from charging C_{OSS} of Syn GaN: $I_{DS} = C_{(V_{bus}-V_{DS})} * dv/dt$
 - Displacement current of discharging C_{OSS} of Rec GaN cannot be directly captured by oscilloscope: $I_{Coss} = C_{oss} * dv/dt$
 - Current through Rec GaN channel consists of two part above: $I_{ch, Rec} = I_{DS} + C_{oss} * dv/dt$

$$\text{Cap Loss(Rec FET)} = \int_0^{V_{bus}} C_{OSS} * V_{DS} dV \quad \text{Cap Loss(Syn FET)} = \int_0^{V_{bus}} C_{OSS} * (V_{bus} - V_{DS}) dV = V_{bus} * Q_{oss} - \int_0^{V_{bus}} C_{OSS} * V_{DS} dV$$

$$\text{Total cap Loss} = V_{bus} * Q_{oss}$$

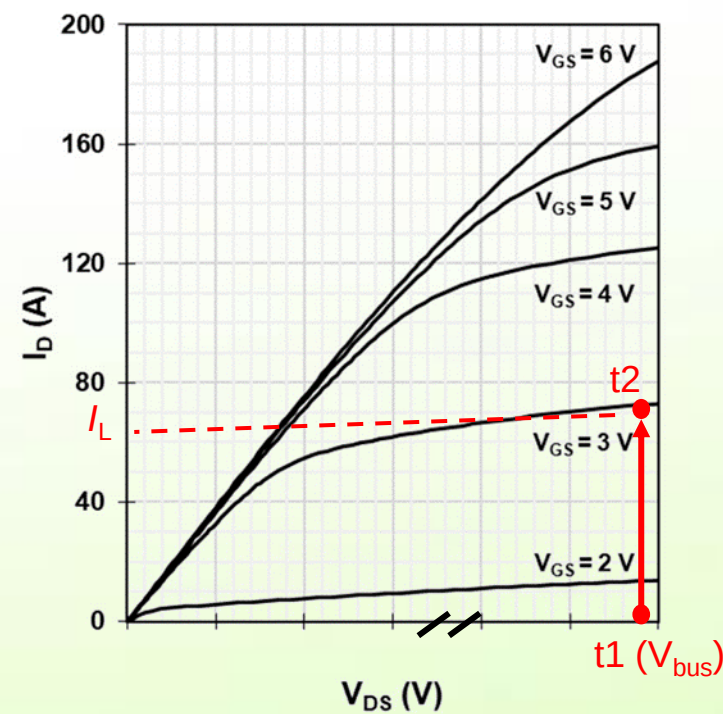
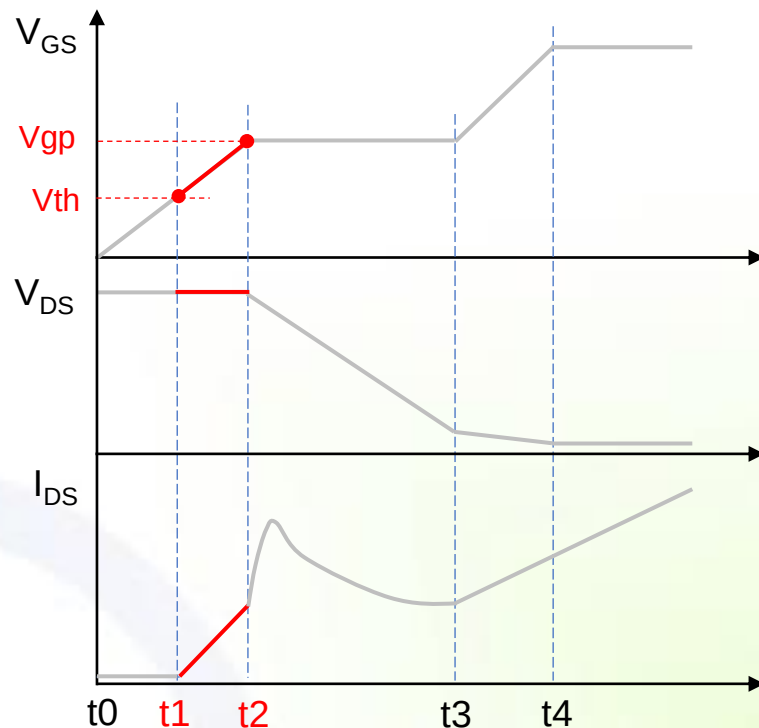
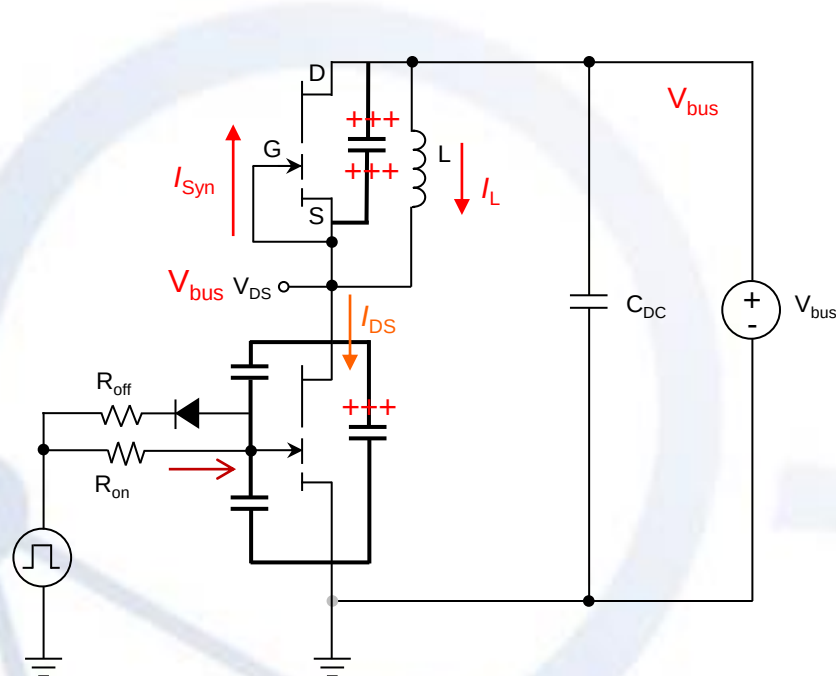
HSW turn-on transient: V_{goff} to V_{th}



$t_0 \sim t_1$, gate drive charges C_{iss} of Rect GaN:

- V_{GS} of Rect GaN rises from 0 to V_{th} , and $V_{DS} = V_{bus}$. No current flows through Rectifier GaN.
- Load current flows through inductor and Syn GaN.
- Until V_{GS} of Rect GaN reaches to its V_{th} , load current starts to commute and flows through it.

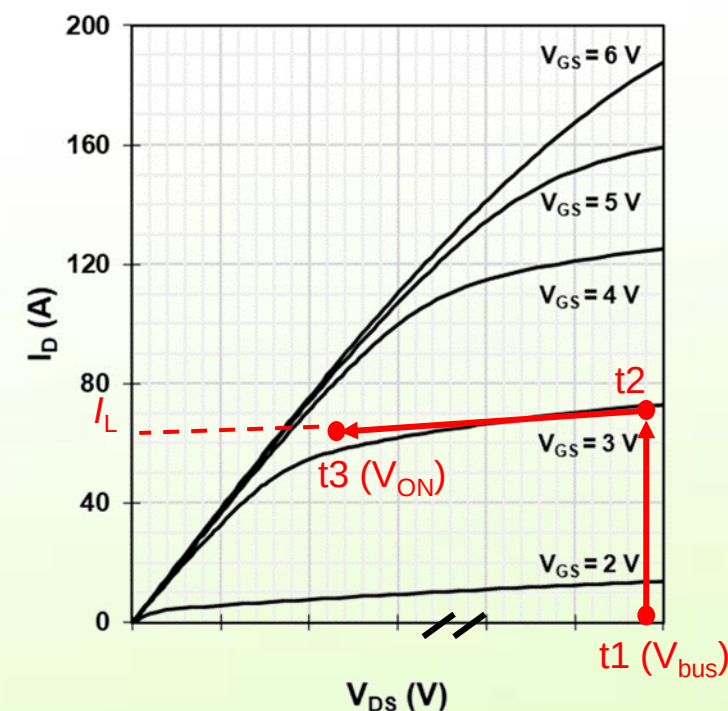
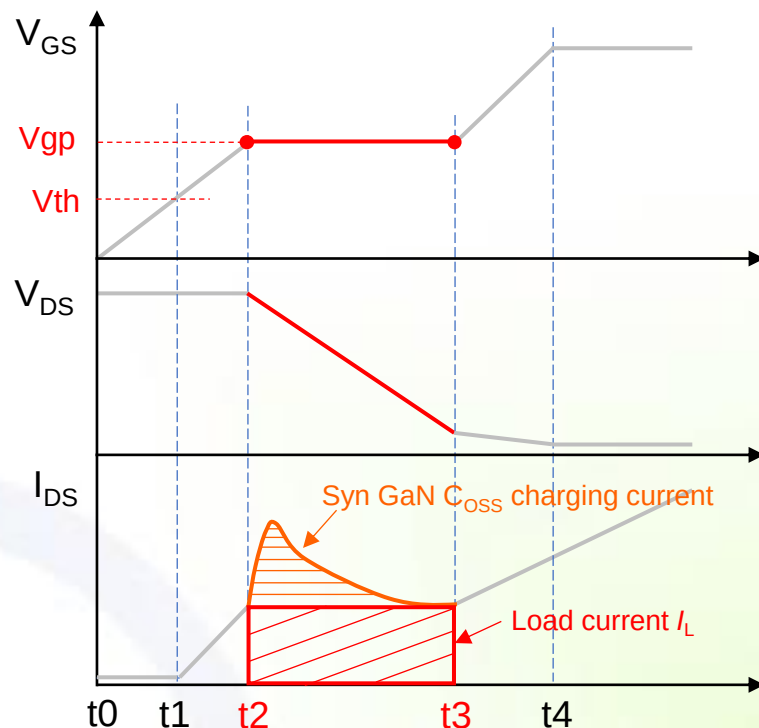
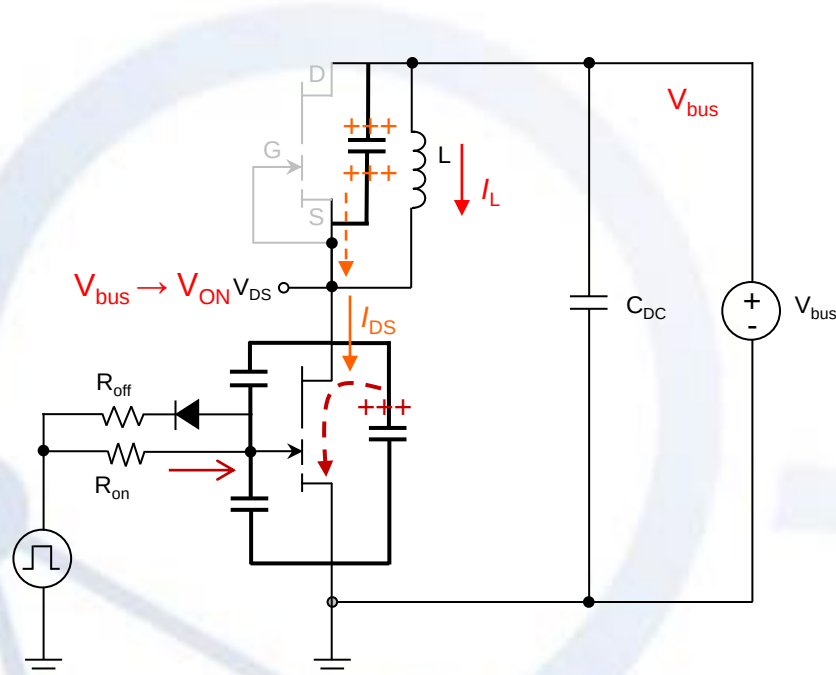
HSW turn-on transient: current commutation



t1~t2, current commutation [load current commutates from Syn GaN to Rec GaN]:

- As V_{GS} of Rec GaN reaches its V_{th} , current starts to flow through Rec GaN. Load current gradually commutates from Syn GaN to Rec GaN, as V_{GS} increases;
- During current commutation, the gate driver charges C_{iss} until Rec GaN has current capability of I_L . [$I_{DS, V_{GS}=V_{gp}} = I_L$]
- When $V_{GS} = V_{gp}$ (Miller plateau, $= V_{th} + I_L/g_m$), all the inductive-load current flows through the Rec GaN.
- In this duration, Rec GaN I_{DS} overlaps with V_{DS} , and **I-V overlap loss** dominates and can be calculated by integrating I & V .

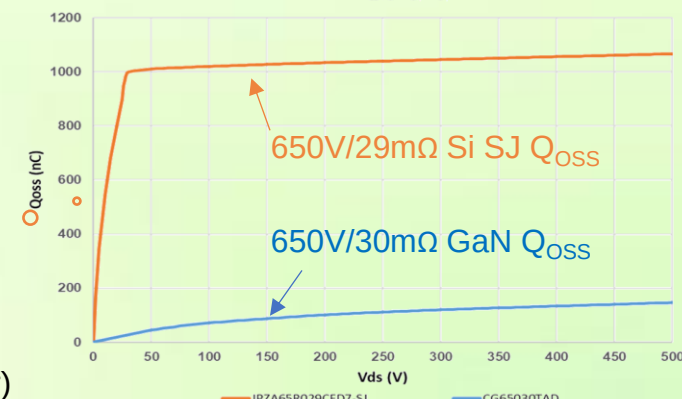
HSW turn-on transient: voltage commutation



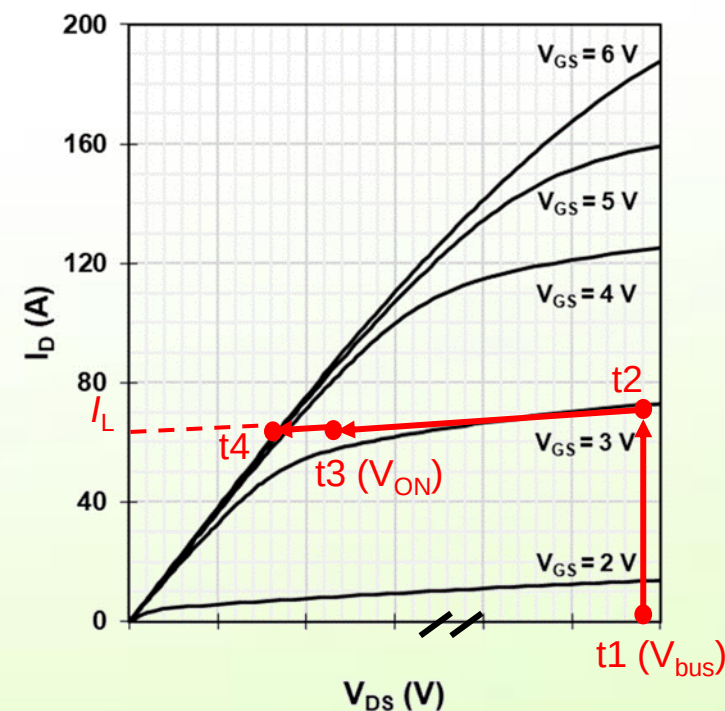
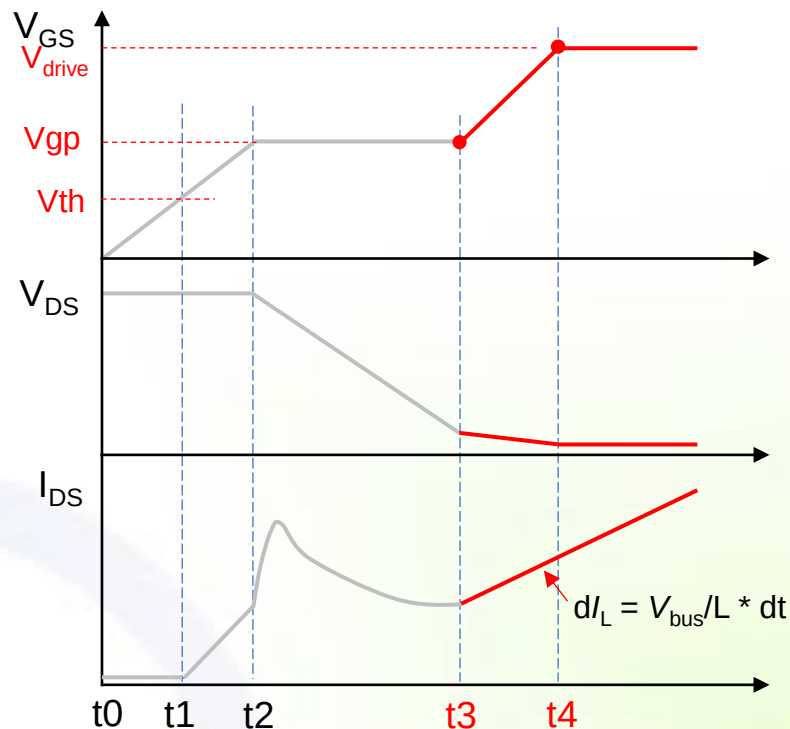
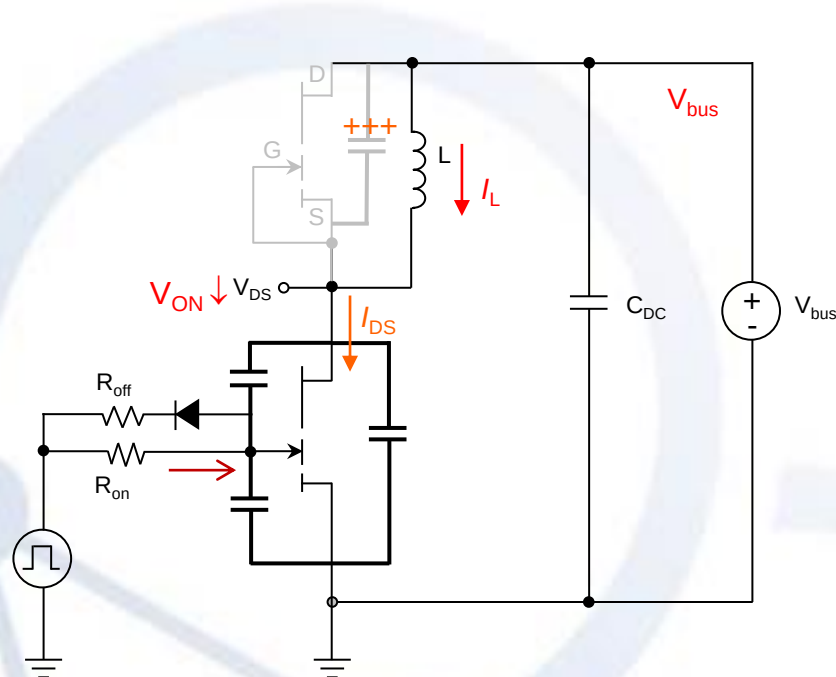
t2~t3, voltage commutation [Rec GaN V_{DS} drops to $V_{ON} = I_L \cdot R_{dson}(V_{GS}=V_{gp})$]:

- As V_{GS} of Rec GaN reaches V_{gp} , all the inductive-load current flows through Rec GaN;
- Then, Rec GaN C_{OSS} starts to discharge from V_{bus} to V_{ON} & Syn GaN C_{OSS} starts to charge to V_{bus}
- Rec GaN C_{OSS} discharging cannot be captured, but Syn GaN C_{OSS} charging can be recognized from I_{DS} waveform
- During this duration, the loss on Rec GaN consists of **2 main parts**:
 - I-V overlap loss**
 - Cap loss from Syn/Rec GaN charging/discharging:** $V_{bus} \cdot Q_{OSS}$ (if Syn/Rec GaN feature the same part number)

GaN features much lower Q_{OSS} and switching loss

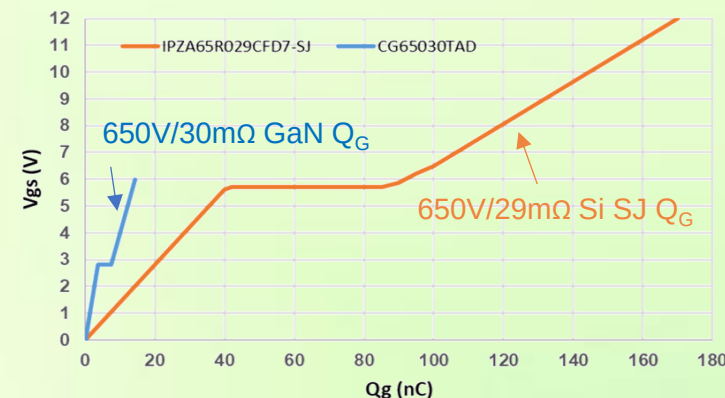


HSW turn-on transient: gate over-drive

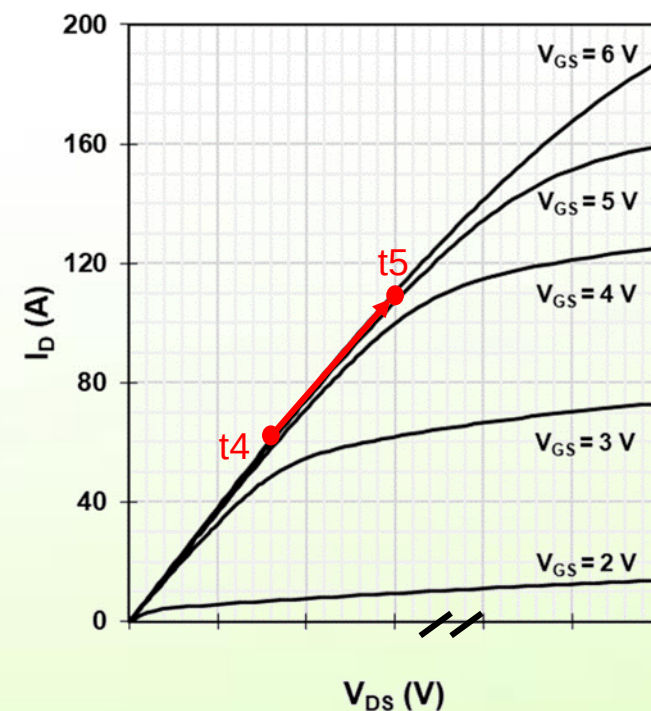
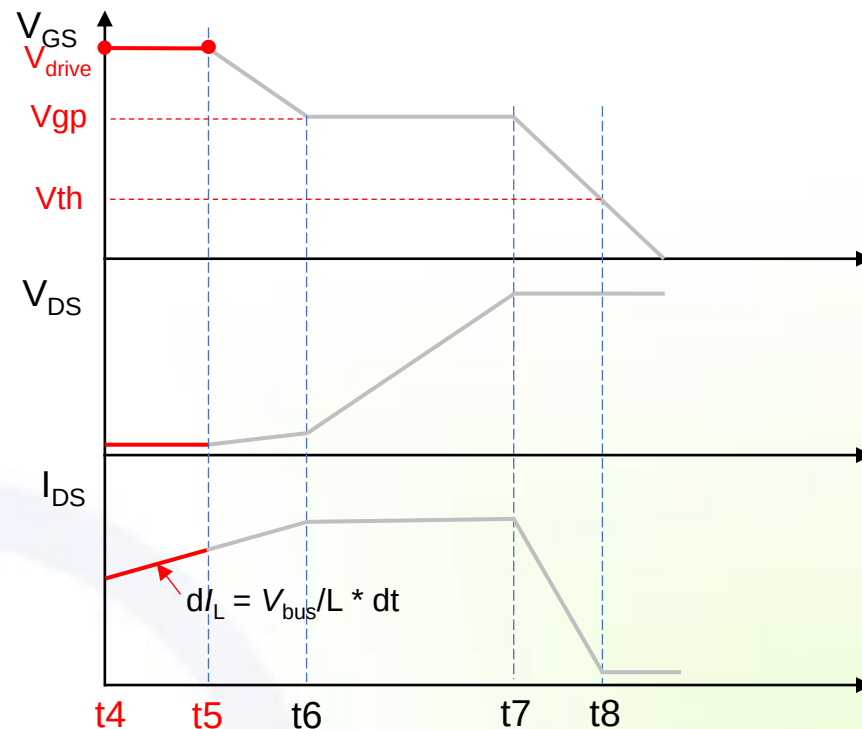
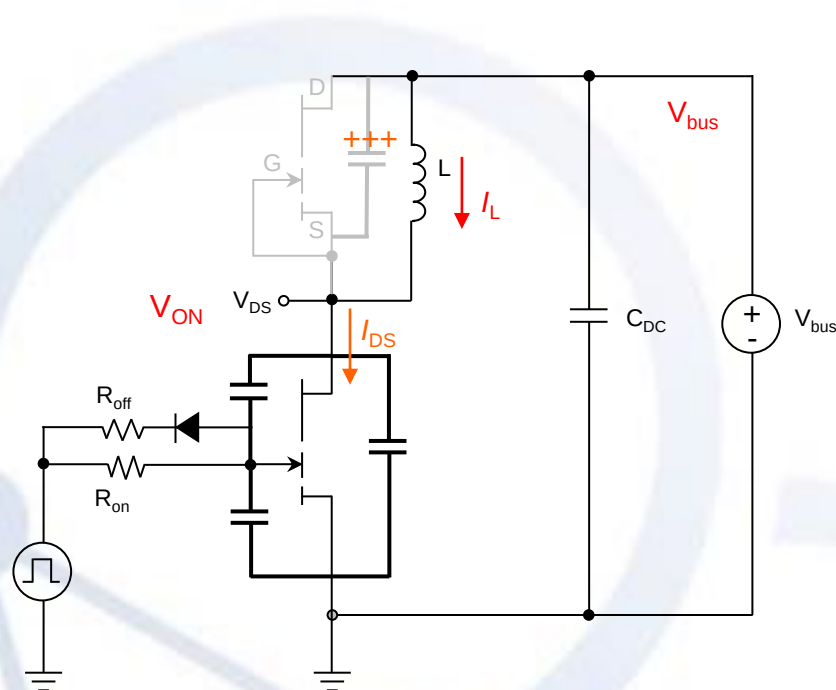


t3~t4, gate over-drive to make GaN fully turn-on:

- Gate driver continues to charge C_{iss} from V_{gp} to V_{drive} (e.g. 6V), making GaN FET fully turn-on
- Comparing to Si SJ, GaN FET features much lower gate charge Q_G (as shown in right plot)
- $V_{ON} = I_L * R_{ds(on)}$ ($V_{GS} = V_{drive}$). The recommended gate drive voltage for CloudSemi E-mode GaN FET is 5.5~6.5V.
- After $t4$, inductive load will continue to excite, following $dI_L = V_{bus}/L * dt$
- Conduction loss on Rec GaN FET dominates in this duration



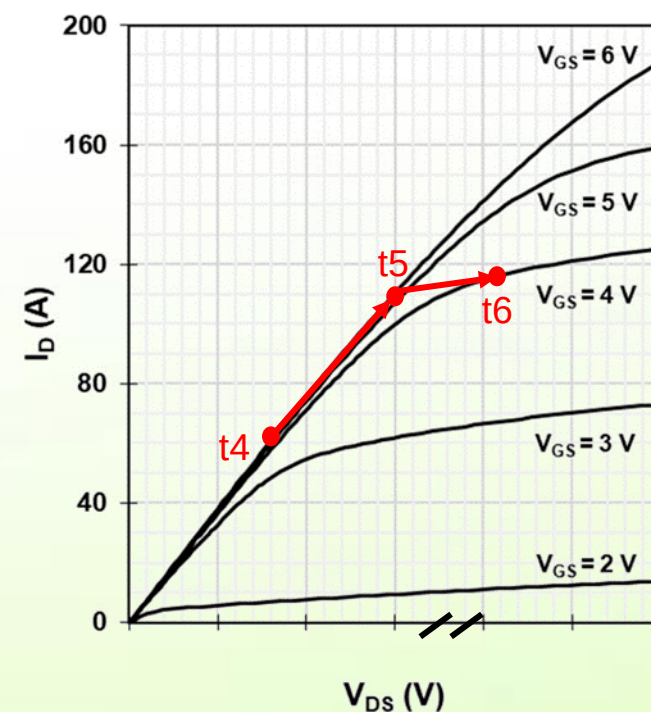
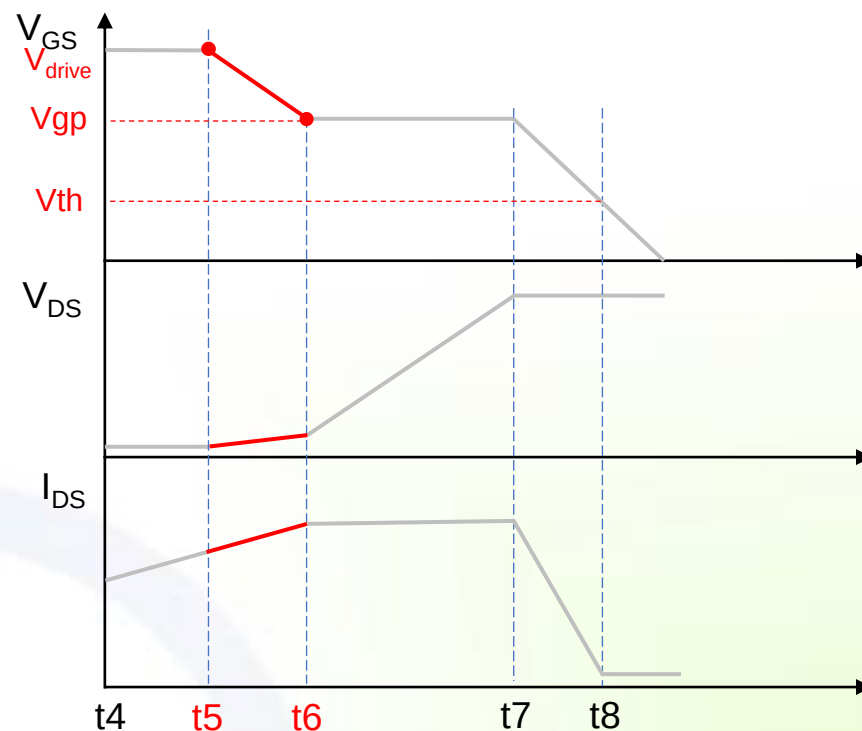
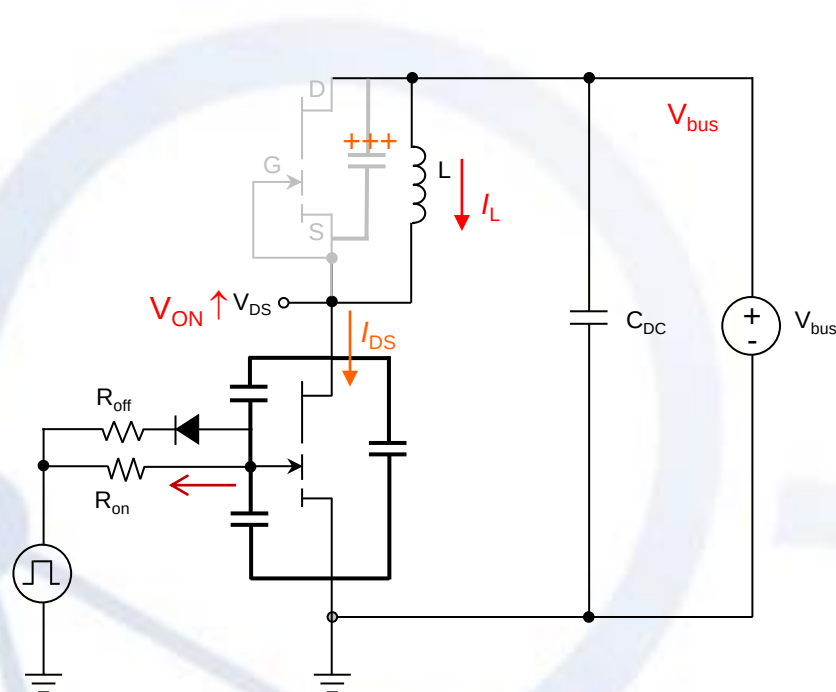
Turn-on period: excitation



t4~t5, inductive load excitation:

- $dI_L = V_{bus}/L * dt$, $I_{DS} = I_L$
- Ciss stops charging
- Current flowing through GaN channel gradually increases
- Rec GaN FET works in linear region.
- Conduction loss on Rec GaN FET dominates in this duration

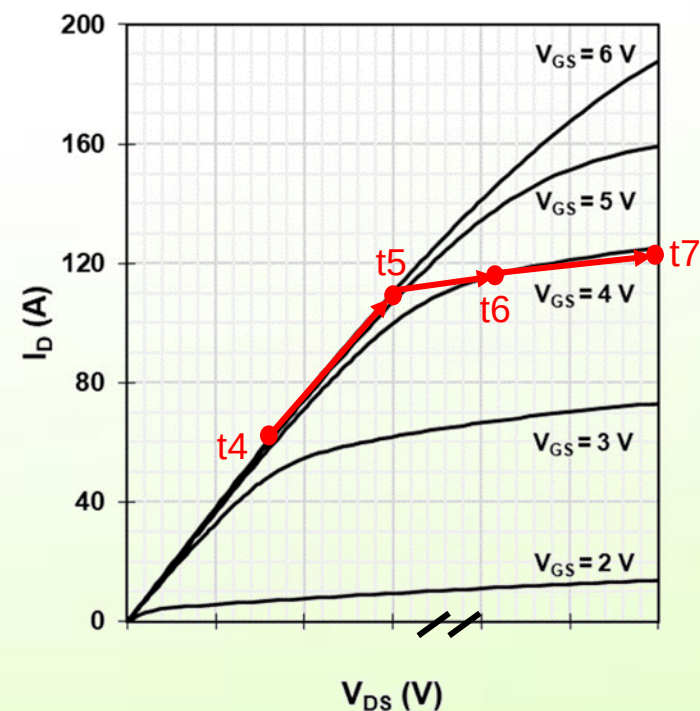
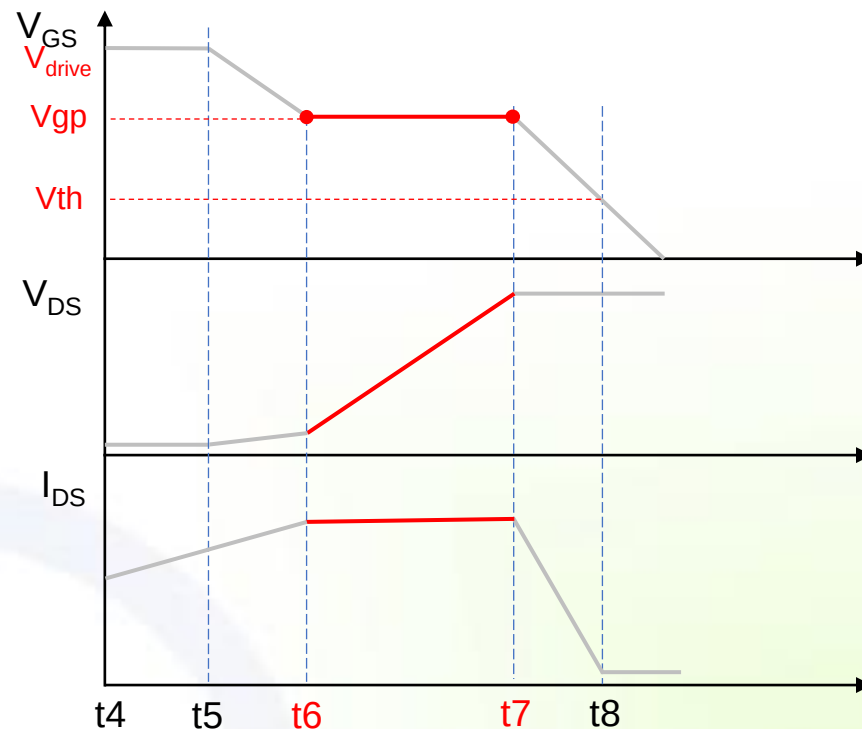
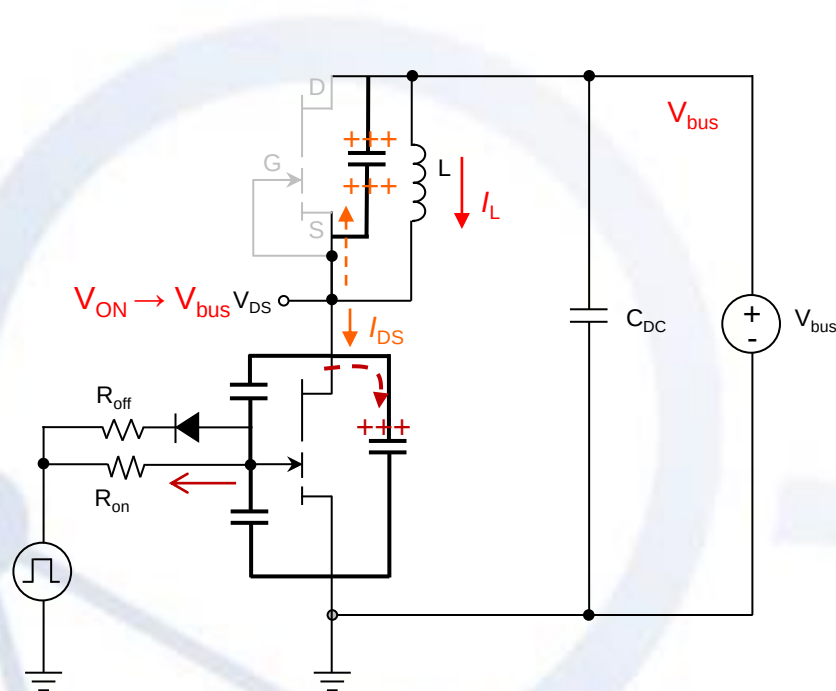
HSW turn-off transient: $V_{GS} \rightarrow V_{gp}$



t5~t6, C_{iss} starts discharging:

- C_{iss} of Rec GaN starts to discharge, until GaN enters saturation mode ($V_{GS} = V_{gp}$, $I_{dsat} = I_L$).
- Here, $V_{gp} = V_{th} + I_L/g_m$
- Rec GaN FET works from linear region to saturation region (as output curves in this slide)
- Conduction loss on Rec GaN FET dominates in this duration

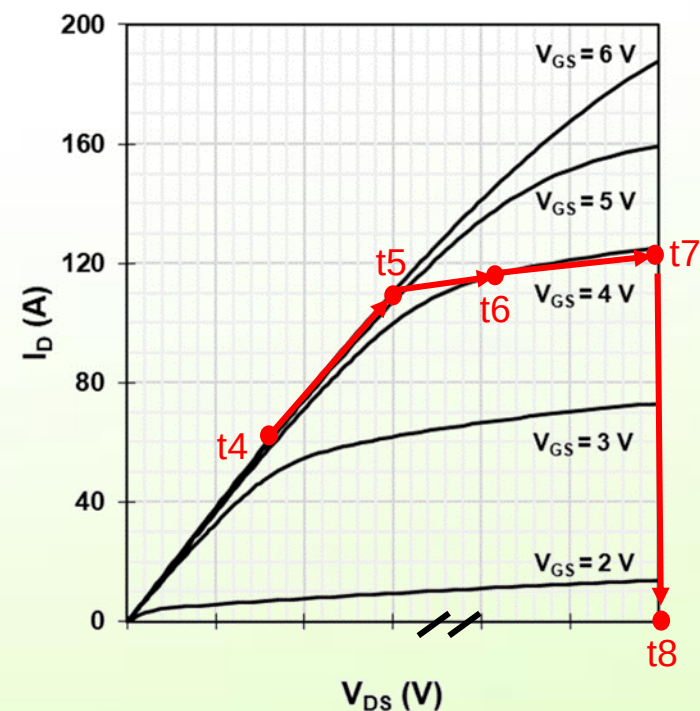
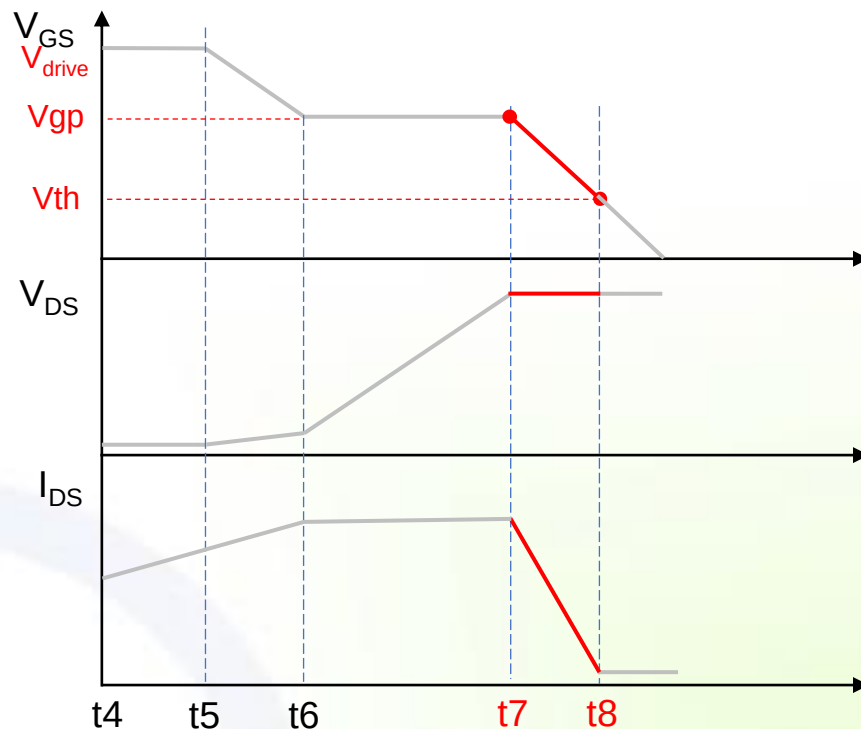
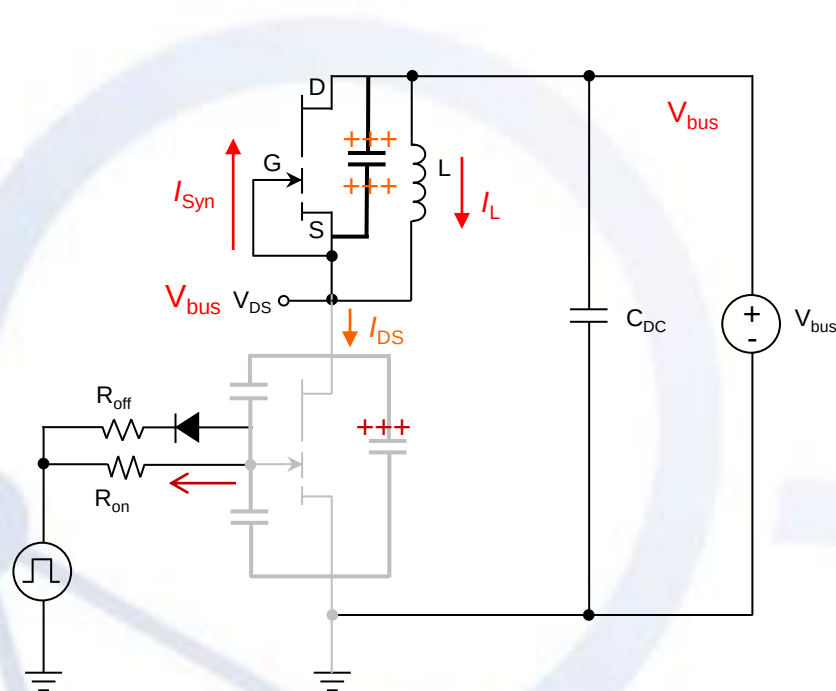
HSW turn-off transient: voltage commutation



t6~t7, voltage commutation (Rec GaN V_{DS} rises to V_{bus}):

- Load current charges the switching node (charging C_{OSS} of Rec GaN, discharging C_{OSS} of Syn GaN)
- Parameter of Q_{OSS} is crucial, and determines charging/discharging speed (i.e. switching speed)
- Power loss on Rec GaN mainly comes from **I-V overlap loss**

HSW turn-off transient: current commutation

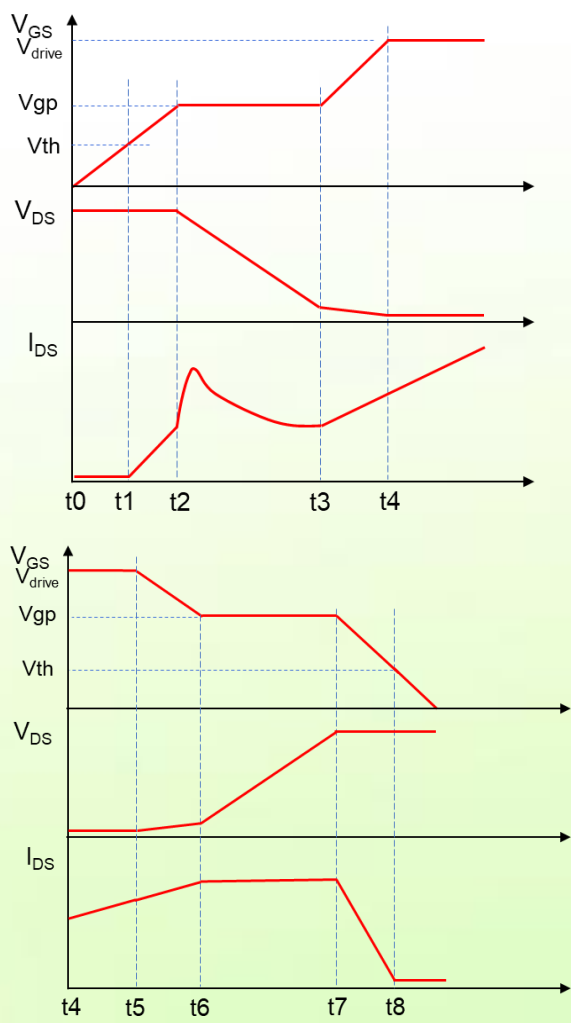


t7~t8, current commutation [load current commutates from Rec GaN to Syn GaN]:

- As V_{GS} of Rec GaN drops from V_{gp} , load current gradually commutates from Rec GaN to Syn GaN, as V_{GS} decreases;
- During current commutation, the gate driver discharges C_{iss} until Rec GaN has been turned off ($V_{GS} = V_{th}$)
- When Rec GaN $V_{GS} = V_{th}$ (i.e. after t8), all the inductive-load current flows through the Syn GaN.
- Power loss mainly comes from I-V overlap loss

Summary

	V_{GS}	V_{DS}	I_{DS}	P_{loss} on Rec GaN	Loss from
Turn-on transient	$V_{goff} \rightarrow V_{th}$ <i>Start to turn-on</i>	V_{bus}	0	$\sim 0 (V_{bus} * I_{dss})$	Drain leakage
	$V_{th} \rightarrow V_{gp}$ <i>Current commutation</i>	V_{bus}	$0 \rightarrow I_L$	$f_{sw} * \int I_{DS} V_{DS} dt$	I-V overlap
	V_{gp} <i>Voltage commutation</i>	$V_{bus} \rightarrow V_{ON}$	$I_L + C_{(V_{bus}-V_{DS})} * dv/dt$	$f_{sw} * (\int I_{DS} V_{DS} dt + E_{oss})$	I-V overlap C_{OSS} of Syn/Rec GaN
	$V_{gp} \rightarrow V_{drive}$ <i>Gate fully turn-on</i>	$V_{ON} \downarrow$	$I_L (dI_L = V_{bus}/L * dt)$	$f_{sw} * \int I_{DS} V_{DS} dt$	Conduction loss
ON-state duration	V_{drive}	V_{ON} slightly rises ($= I_L * R_{dson}$)	$I_L (dI_L = V_{bus}/L * dt)$	$\frac{Ip^2 + Iv^2 + IpIv}{3} * R_{dson} * duty$	Conduction loss
Turn-off transient	$V_{drive} \rightarrow V_{gp}$ <i>Start to turn-off</i>	$V_{ON} \uparrow$	$I_L (dI_L = V_{bus}/L * dt)$	$f_{sw} * \int I_{DS} V_{DS} dt$	Conduction loss
	V_{gp} <i>Voltage commutation</i>	$V_{ON} \rightarrow V_{bus}$	I_L	$f_{sw} * \int I_{DS} V_{DS} dt$	I-V overlap
	$V_{gp} \rightarrow V_{th}$ <i>Current commutation</i>	V_{bus}	$I_L \rightarrow 0$	$f_{sw} * \int I_{DS} V_{DS} dt$	I-V overlap
	$V_{th} \rightarrow V_{goff}$ <i>Gate fully turn-off</i>	V_{bus}	0	$\sim 0 (V_{bus} * I_{dss})$	Drain leakage



More information of GaN FET loss calculation in switch-mode power supply could be found in application note [CGAN004](#).

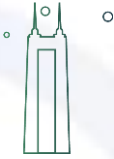
Powering the Dreams by CloudSemi GaN



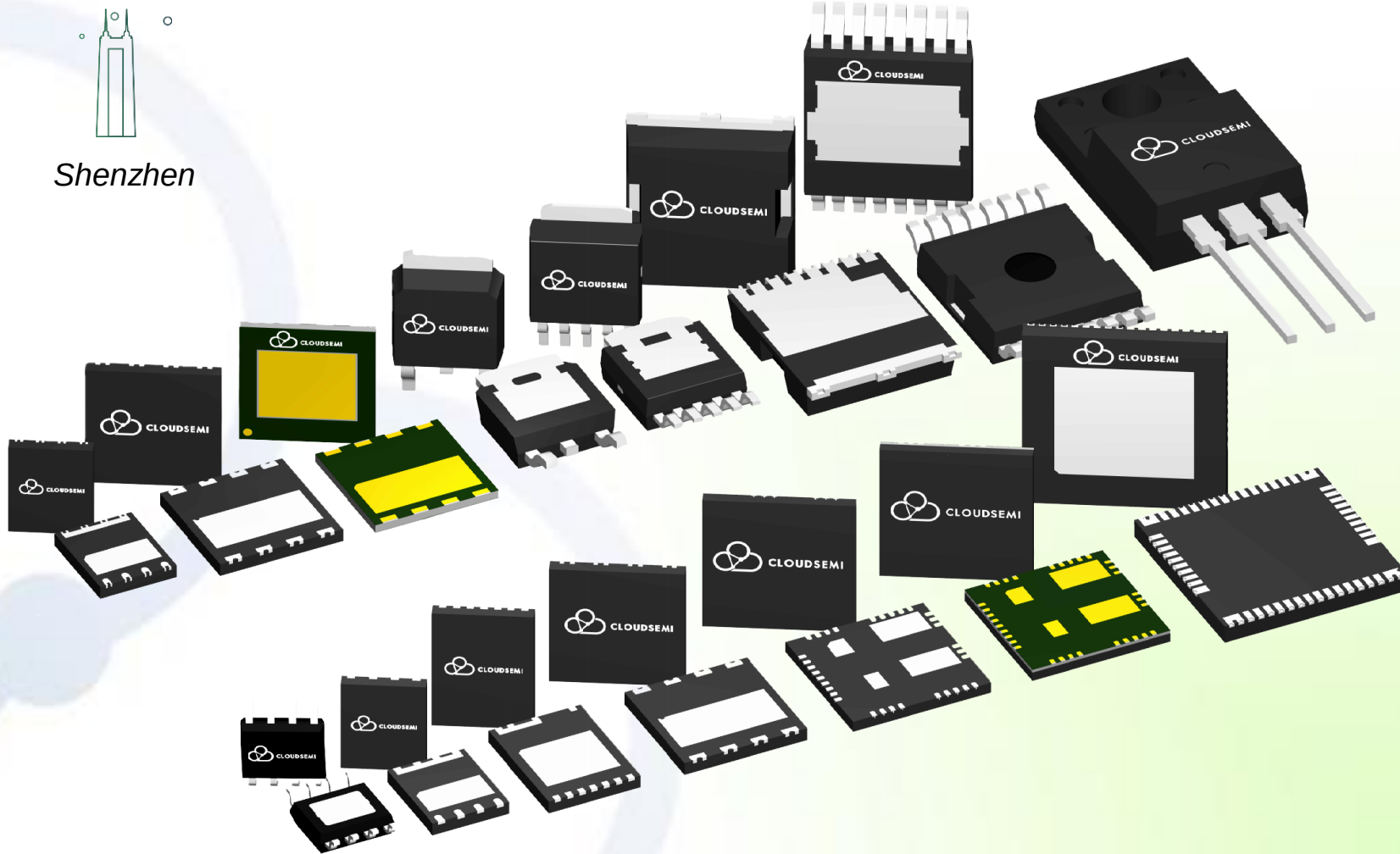
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Thank You!

Powering the Dreams!

